

L Number	Hits	Search Text	DB	Time stamp
1	594	(257/330).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/05/16 10:47
2	288	(257/331).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/05/16 11:04
3	547	(257/341).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2002/05/16 11:05

L Number	Hits	Search Text	DB	Time stamp
1	258	(257/343).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/16 13:07
2	691	(257/329, 332, "333").CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/16 13:08

L Number	Hits	Search Text	DB	Time stamp
1	0	semiconductor and (plateable adj metal) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/16 14:13
2	8204	semiconductor and plat\$4 and metal and (gate adj electrode)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/16 14:17
3	226	(semiconductor and plat\$4 and metal and (gate adj electrode)) and (plat\$4 adj metal)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/05/16 14:20